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## WEBINARS

Date	Time	Topic
April 9, 2020	11:00am CEST	<a href="#">Exploring the Potential of the Sideband KPFM Mode</a>
April 17, 2020	9:00am PDT	<a href="#">3D Printing via SLA and DLP</a>
April 20, 2020	9:00am CST	<a href="#">Recent Innovations in Scanning Tunneling Microscopy (STM) &amp; Park SmartScan</a>
April 29, 2020	9:00am PDT	<a href="#">Investigation of Lithium Ion Battery Electrodes Using Pinpoint SSRM in Vacuum</a>
April 29, 2020	11:00am CEST	<a href="#">Advanced Piezoresponse Force Microscopy – optimizing PFM for your applications from off resonance to frequency tracking</a>

## Live Demos

Date	Time	Topic
April 15, 2020	10:30am CEST	<a href="#">Quick automation set-up for research applications (SmartScan™ &amp; StepScan™)</a>
April 17, 2020	12:00pm PDT	<a href="#">SmartScan Topography Imaging</a>
April 22, 2020	10:30am CEST	<a href="#">From automatization in research to quality control (on NX20 Large Sample AFM)</a>
May 6, 2020	16:00pm CEST	<a href="#">Full-automation in-line capabilities with the NX-Wafer</a>

## WEBINAR RECORDINGS

### Topic

[Conductive Atomic Force Microscopy used for Two-Dimensional Materials and Nanoelectronics \(Chinese\)](#)

[Nanotechnology in Plastics and Packaging](#)

[Surface Plasmon Resonance Spectroscopy Tandem with AFM](#)

[Unraveling Amyloid Formation and Heterogeneity by AFM Single Molecule Statistical Analysis](#)

- for more see next page

## EDUCATIONAL VIDEOS

### Topic

[AFM Principle](#)

[Non-Contact Mode](#)

[Dynamic Contact EFM \(DC-EFM\)](#)

### Topic

[Conductive AFM](#)

[Scanning Ion Conductance Microscopy \(SICM\)](#)

[Magnetic Force Microscopy \(MFM\)](#)





## WEBINAR RECORDINGS

### Topic

- [Nanotechnology in Plastics and Packaging](#)
- [Surface Plasmon Resonance Spectroscopy Tandem with AFM](#)
- [Viscoelastic Surfactants and Oilfield Chemicals](#)
- [Physical Properties of Emergent 2D materials with AFM](#)
- [2D Nanomaterials for Smart Coatings and Fluids](#)
- [Electrochemical Capacitors: Fundamentals, Materials, and Advanced Characterization](#)
- [Nanostructured Polymer Brushes With AFM](#)



## EDUCATIONAL WEBINARS

### “AFM TECHNIQUES”

### Topic

- [Atomic Force Microscopy PinPoint Nanomechanical Mode for Nanoscale Modulus Mapping – Cantilever Modulus and Applied Force](#)
- [PinPoint Piezoelectric Force Microscopy](#)
- [Electrochemical Atomic Force Microscopy \(EC-AFM\)](#)
- [PinPoint Nanomechanical Imaging Using Probes of Various Cantilever Stiffness](#)
- [Scanning Ion Conductance Microscopy \(SICM\) and Scanning Electrochemical Microscopy \(SECM\)](#)



## EDUCATIONAL VIDEOS

### “How AFM works?”

### Topic

- [AFM Principle](#)
- [Contact Mode](#)
- [Non-Contact Mode](#)
- [Tapping Mode](#)
- [Dynamic Contact EFM \(DC-EFM\)](#)
- [Electrostatic Force Microscopy \(EFM\)](#)
- [Conductive AFM](#)
- [IV Spectroscopy](#)
- [Scanning Capacitance Microscopy \(SCM\)](#)
- [Scanning Kelvin Probe Microscopy \(KPFM\)](#)

### Topic

- [Scanning Ion Conductance Microscopy \(SICM\)](#)
- [Force Distance Spectroscopy](#)
- [Magnetic Force Microscopy \(MFM\)](#)
- [Force Modulation Microscopy \(FMM\)](#)
- [Lateral Force Microscopy \(LFM\)](#)
- [NanoIndentation](#)
- [Nanolithography](#)
- [Scanning Thermal Microscopy \(SThM\)](#)





## NANOSCIENTIFIC TALKS



Topic	Speaker
<b>Nanomechanics &amp; Electrical Characterization</b>	
<a href="#">External Energy Assisted Nanomachining Using Soft AFM Probes</a>	<a href="#">Dr. Jia Deng, Binghamton University - SUNY, NSS US 2019</a>
<a href="#">Atomic Force Microscopies to study Electronic Properties and Strain in Thin Films for Flexible Electronics</a>	<a href="#">Tobias Cramer, University of Bologna, Italy   NSF 2018</a>
<a href="#">The growth of organic ultra-thin films on silicon oxides with variable vacancy states: a Scanning Force Microscopy approach</a>	<a href="#">Cristiano Albonetti, CRN – ISMN, Italy   NSF 2018</a>
<a href="#">Detection of Hydrophobic Interactions on Rough Surfaces via Atomic Force Microscopy: from Measurement to Modelling</a>	<a href="#">Urs Peuker, TU Bergakademie Freiberg, Germany NSF 2018</a>
<b>AFM Methodology</b>	
<a href="#">Chemical Sensitivity for Scanning Probe Microscopy</a>	<a href="#">Lukas Eng, Tech. University Dresden   NSF 2018</a>
<a href="#">Electrochemical measurements of single nanoparticles</a>	<a href="#">Kim McKelvey, Trinity College Dublin   NSF 2019</a>
<a href="#">Learning in Fundamental Atomistic Processes Using Suspended Silicon Nanowires</a>	<a href="#">Dr. Ye Tao, Rowland Institute at Harvard   NSS US 2018</a>
<a href="#">3D Nanoscaffold Cantilevers for Potential Applications in High Speed Wafer Scale Imaging</a>	<a href="#">Hoa Le, The Rowland Institute at Harvard, NSS US 2019</a>
<a href="#">Scanning Capacitance Spectroscopy for Dopant Analysis on Nanoscale Semiconductor Devices</a>	<a href="#">Phil Kaszuba, Global Foundries US   NSS US 2019</a>
<a href="#">Measuring Ions and Electrons with Nanoscale Pipettes</a>	<a href="#">Dr. Lane Baker, Indiana University, NSS U 2019</a>
<b>Life Science and Biotechnology</b>	
<a href="#">Revisiting the Early Aggregation of Amyloids by AFM Single Molecule Statistical Analysis</a>	<a href="#">Francesco S. Ruggeri, University of Cambridge   NSF 2018</a>
<a href="#">Probing the Intersection of Nanotechnology and Biology</a>	<a href="#">Dr. Nathaniel Cady, Colleges of Nanoscale Science &amp; Engineering   NSS US 2019</a>
<a href="#">Metallo-DNA molecules as a tool for nanoscience and nanotechnology</a>	<a href="#">Miguel A. Galindo, CIC, University of Granada   NSF 2019</a>
<a href="#">AFM Applications in biology and medicine</a>	<a href="#">Malgorzata Lekka, Institute of Nuclear Physics, Poland   NSF 2019</a>
<b>Organic Interfaces and Semiconductors</b>	
<a href="#">Measurement Challenges arising from New Semiconductor Materials and Structures for Integrated Circuits</a>	<a href="#">Dr. Alain Diebold, SUNY Polytechnic Institute   NSS US 2019</a>
<a href="#">Characterizing photoelectric and ferroelectric properties of materials with scanning probe microscope</a>	<a href="#">Akash Bhatnagar, Centre for Innovation Competence SiLi-nano   NSF 2019</a>
<a href="#">SPM Study of Tribo-Photovoltaic Effect in Metal, Semiconductor Moving Contacts</a>	<a href="#">Jun Liu, University at Buffalo   NSS US 2019</a>